

P-Channel 30 V (D-S) MOSFET

| PRODUCT SUMMARY | | | | | | | |
|---------------------|-----------------------------------|--------------------|-----------------------|--|--|--|--|
| V _{DS} (V) | $R_{DS(on)}(\Omega)$ | I _D (A) | Q _g (Typ.) | | | | |
| - 30 | 0.010 at V _{GS} = - 10 V | - 50 ^d | 43.1 nC | | | | |
| - 30 | 0.014 at V _{GS} = -4.5 V | - 40 ^d | 43.1110 | | | | |

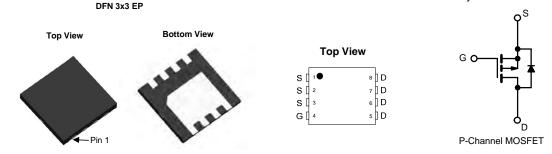
FEATURES

- Trench Power MOSFET
- Low On-Resistance for Low Voltage Drop
- 100 % R_q and UIS Tested

ROHS COMPLIANT HALOGEN FREE

APPLICATIONS

- Battery, Load and Adaptor Switches
 - Notebook Computers
 - Notebook Battery Packs



| Parameter | Symbol | Limit | Unit | |
|--|-----------------------------------|------------------|------------------------|----|
| Drain-Source Voltage | V _{DS} | - 30 | V | |
| Gate-Source Voltage | V _{GS} | ± 20 | | |
| | T _C = 25 °C | | - 50 ^d | |
| Continuous Drain Current (T = 150 °C) | T _C = 70 °C | 1 , [| - 50 ^d | |
| Continuous Drain Current (T _J = 150 °C) | T _A = 25 °C | l _D | - 23.1 ^{a, b} | |
| | T _A = 70 °C | | - 18.4 ^{a, b} | |
| Pulsed Drain Current (t = 100 μs) | I _{DM} | - 100 | A | |
| Continuous Courses Drain Diade Current | T _C = 25 °C | | - 50 ^d | |
| Continuous Source-Drain Diode Current | T _A = 25 °C | l _s – | - 4.1 ^{a, b} | |
| Avalanche Current | 1 0.1 ml l | I _{AS} | - 25 | |
| Single-Pulse Avalanche Energy | L = 0.1 mH | E _{AS} | 31.2 | mJ |
| | T _C = 25 °C | | 48 | |
| Maximum Dayer Dissipation | T _C = 70 °C | P _D | 31 | w |
| Maximum Power Dissipation | T _A = 25 °C | | 5 ^{a, b} | VV |
| | T _A = 70 °C | 1 | 3.2 ^{a, b} | |
| Operating Junction and Storage Temperature Range | T _J , T _{stg} | - 55 to 150 | °C | |
| Soldering Recommendations (Peak Temperature) ^{e, f} | | 260 | | |

| THERMAL RESISTANCE RATINGS | | | | | | |
|---|--------------|-------------------|---------|---------|------|--|
| Parameter | | Symbol | Typical | Maximum | Unit | |
| Maximum Junction-to-Ambient ^{a, c} | t ≤ 10 s | R _{thJA} | 21 | 25 | °C/W | |
| Maximum Junction-to-Case | Steady State | R _{thJC} | 2.1 | 2.6 | C/VV | |

Notes:

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under steady state conditions is 70 °C/W.
- d. Package limited.
- e. The DFN3X3 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- f. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.



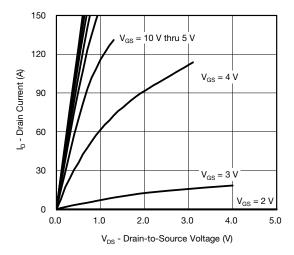
| SPECIFICATIONS ($T_J = 25$ °C) Parameter | Symbol | Test Conditions | Min. | Тур. | Max. | Unit |
|--|----------------------------------|---|-------|--------|--------|--------------|
| Static | Cyllibol | rest conditions | | Typ. | WIGA. | Oilit |
| Drain-Source Breakdown Voltage | V _{DS} | V _{GS} = 0, I _D = - 250 μA | - 30 | | | V |
| V _{DS} Temperature Coefficient | ΔV _{DS} /T _J | , igs 6, ig 200 p | - 00 | - 22 | | mV/°C |
| V _{GS(th)} Temperature Coefficient | $\Delta V_{GS(th)}/T_J$ | I _D = - 250 μA | | 4.1 | | |
| () | ` , | V - V I - 250 uA | - 1.2 | 4.1 | 0.5 | |
| Gate-Source Threshold Voltage | V _{GS(th)} | $V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$ | | | - 2.5 | · |
| Gate-Source Leakage | I _{GSS} | V _{DS} = 0 V, V _{GS} = ± 20 V | | | ± 100 | nA |
| Zero Gate Voltage Drain Current | I _{DSS} | V _{DS} = - 30 V, V _{GS} = 0 V | | | - 1 | μA |
| Zoro Gato Voltago Ziam Gament | .055 | V _{DS} = - 30 V, V _{GS} = 0 V, T _J = 55 °C | - | | - 5 | Π μ/ ι |
| On-State Drain Current ^a | I _{D(on)} | $V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$ | - 30 | | | Α |
| | Б | V _{GS} = - 10 V, I _D = - 15 A | 0.010 | | | Ω |
| Drain-Source On-State Resistance ^a | R _{DS(on)} | V _{GS} = - 4.5 V, I _D = - 10 A | | 0.014 | 0.014 | |
| Forward Transconductance ^a | 9 _{fs} | V _{DS} = - 10 V, I _D = - 15 A | | 60 | | S |
| Dynamic ^b | | | L | L | 1 | |
| Input Capacitance | C _{iss} | | | 5125 | | |
| Output Capacitance | C _{oss} | V _{DS} = - 15 V, V _{GS} = 0 V, f = 1 MHz | | 615 | | pF |
| Reverse Transfer Capacitance | C _{rss} | | | 554 | | - " |
| Treverse Transier Capacitance | Q _g | V _{DS} = - 15 V, V _{GS} = - 10 V, I _D = - 10 A | | 90 | 135 | 135 65 nC |
| Total Gate Charge | | VDS = 13 V, VGS = 10 V, ID = 10 A | | 43.1 | | |
| Gate-Source Charge | Q _{gs} | $V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -10 \text{ A}$ | | 13.6 | 03 | |
| | | VDS = - 13 V, VGS = - 4.3 V, ID = - 10 A | | 28.8 | | |
| Gate-Drain Charge | Q _{gd} | (() () | 0.5 | | 4.0 | |
| Gate Resistance | R _g | f = 1 MHz | 0.5 | 2.4 | 4.8 | Ω |
| Turn-On Delay Time | t _{d(on)} | | | 15 | 30 | |
| Rise Time | t _r | $V_{DD} = -15 \text{ V}, R_{L} = 1.5 \Omega$ | | 12 | 24 | _ |
| Turn-Off DelayTime | t _{d(off)} | $I_D \cong$ - 10 A, $V_{GEN} =$ - 10 V, $R_g =$ 1 Ω | | 58 | 110 | |
| Fall Time | t _f | | | 12 | 24 | ns |
| Turn-On Delay Time | t _{d(on)} | | | 60 | 120 | 115 |
| Rise Time | t _r | $V_{DD} = -15 \text{ V}, R_{L} = 1.5 \Omega$ | | 60 | 120 | |
| Turn-Off DelayTime | t _{d(off)} | $I_D \cong -10 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$ | | 52 | 100 | |
| Fall Time | t _f | j | | 26 | 52 | |
| Drain-Source Body Diode Characteris | tics | | l | 1 | 1 | |
| Continous Source-Drain Diode Current | I _S | T _C = 25 °C | | | - 50 | Λ |
| Pulse Diode Forward Current (100 µs) | I _{SM} | | | | - 100 | - A |
| Body Diode Voltage | V_{SD} | I _S = - 3 A, V _{GS} = 0 | | - 0.74 | - 1.20 | V |
| Body Diode Reverse Recovery Time | t _{rr} | I _F = - 10 A, dl/dt = 100 A/μs, T _J = 25 °C | | 23 | 46 | ns |
| Body Diode Reverse Recovery Charge | Q _{rr} | | | 12 | 24 | nC |
| Reverse Recovery Fall Time | t _a | $\begin{bmatrix} 1 & -1 & 10 & 10 & 10 & 10 & 10 & 10 & $ | | 9 | | ns |
| Reverse Recovery Rise Time | t _b | t _b | | 14 | | 113 |

Notes

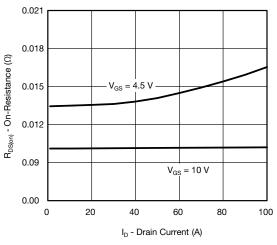
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

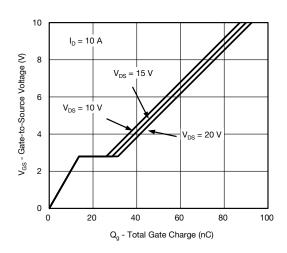




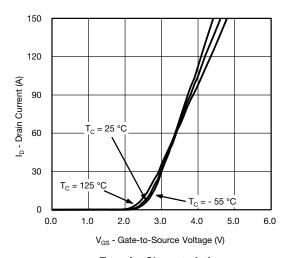
Output Characteristics



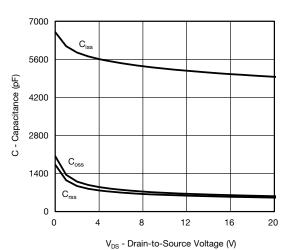
On-Resistance vs. Drain Current



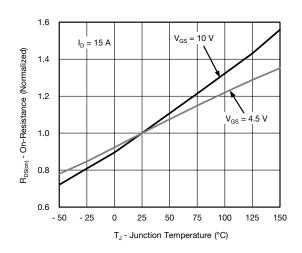
Gate Charge



Transfer Characteristics

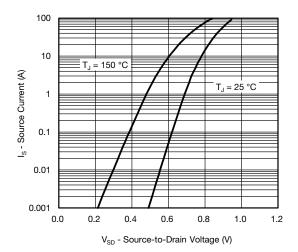


Capacitance

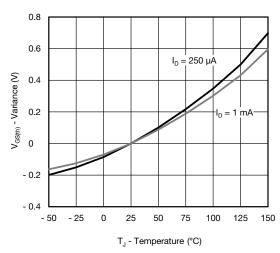


On-Resistance vs. Junction Temperature

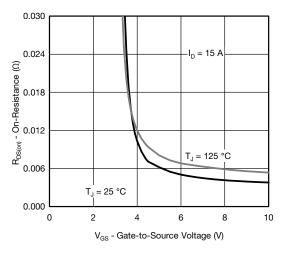




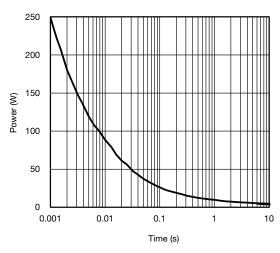
Source-Drain Diode Forward Voltage



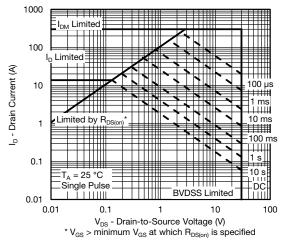
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage

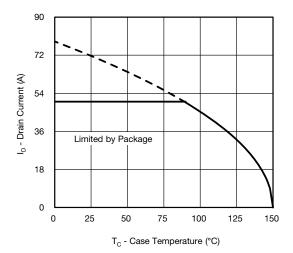


Single Pulse Power, Junction-to-Ambient

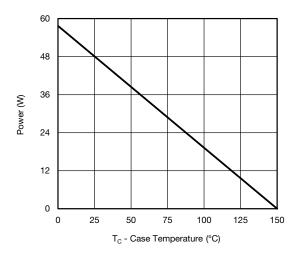


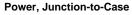
Safe Operating Area

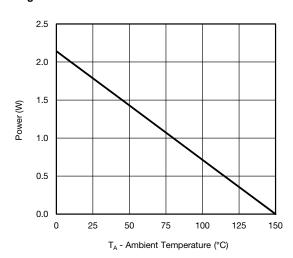




Current Derating*





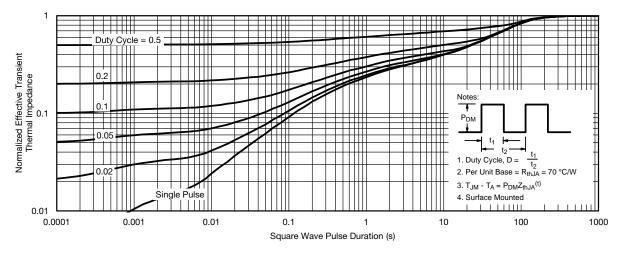


Power Derating, Junction-to-Ambient

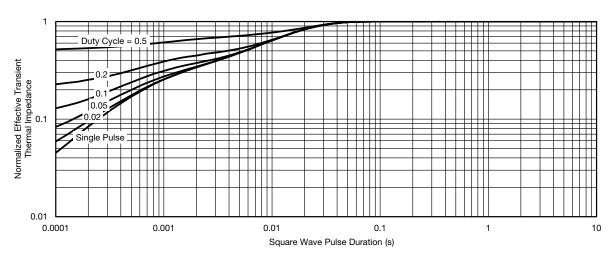
服务热线:400-655-8788 5

^{*} The power dissipation P_D is based on $T_{J(max.)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



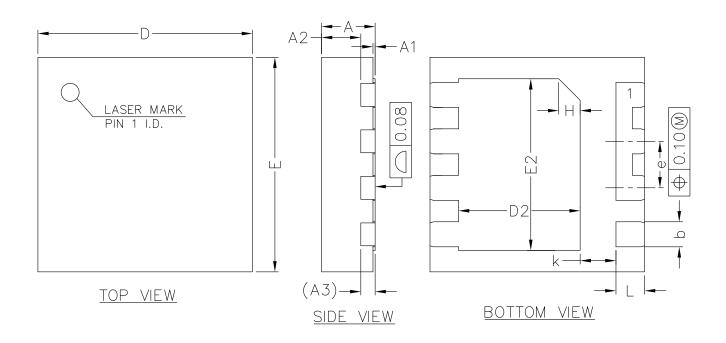


Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case







COMMON DIMENSIONS
(UNITS OF MEASURE=MILLIMETER)

| SYMBOL | MIN | NOM | MAX | |
|--------|---------|------|------|--|
| А | 0.70 | 0.75 | 0.80 | |
| A1 | 0.00 | 0.02 | 0.05 | |
| A2 | 0.50 | 0.55 | 0.60 | |
| А3 | 0.20REF | | | |
| Ь | 0.30 | 0.35 | 0.40 | |
| D | 2.90 | 3.00 | 3.10 | |
| E | 2.90 | 3.00 | 3.10 | |
| D2 | 1.60 | 1.70 | 1.80 | |
| E2 | 2.30 | 2.40 | 2.50 | |
| е | 0.55 | 0.65 | 0.75 | |
| K | 0.40 | 0.50 | 0.60 | |
| L | 0.35 | 0.40 | 0.45 | |



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